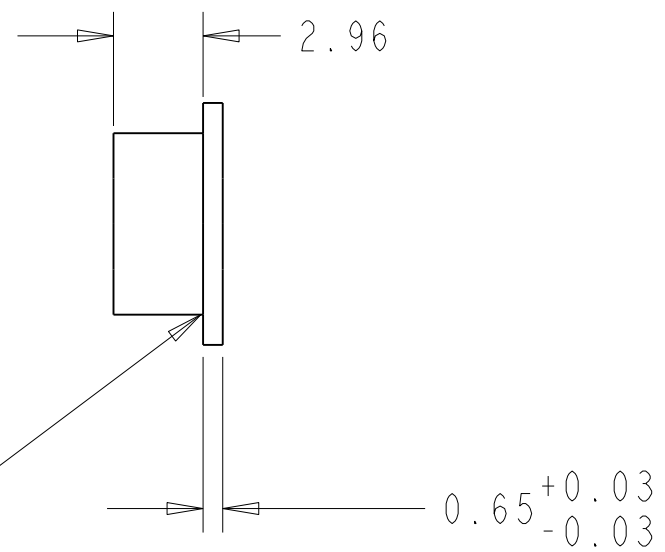
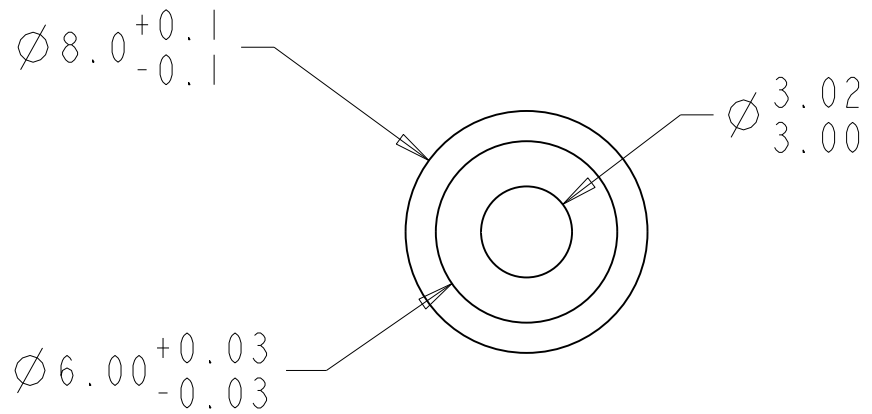




REV				DWG	CHK	DATE	CHANGES				DESCRIPTION				VICTREX PEEK											
UNLESS OTHERWISE SPECIFIED							SHOP ORDERS				ERNEST ORLANDO LAWRENCE BERKELEY NATIONAL LABORATORY UNIVERSITY OF CALIFORNIA - BERKELEY				MATERIAL											
TOLERANCES	X.X ±0.1	FRAC. ±1/64	ACCT NO.	SEE J.O	NO. 180	DATE ISSD	SER NO.	ATLAS PIXEL DETECTOR DISK SECTOR, MODULE LOCAL SUPPORT T-WASHER, SECTOR MOUNT				MICROFILMED:		DWG. TYPE PART		SCALE: 4.000		DO NOT SCALE PRINTS								
	X.XX ±0.03	Angles ±1.00°	DEL TO	JS WIRTH	DATE RECD																					
	X.XXX ±0.010	FINISH 125 (µm)	SURFACE TREATMT	CHROMIC ETCH																						
	DO NOT SCALE PRINT		IDENT METHOD		TAG																					
THREADS ARE CLASS 2							PROJECT NUMBER				ATL-IP-ED-0030				PATENT CLEAR:		DESIGN ACCT. NO.		CATEGORY CODE		DWG. NO.		SIZE		REV.	
CHAMFER ENDS OF ALL SCREW THREADS 30°							PROJECT NAME				US ATLAS SILICON SUBSYSTEM				PIAP-11		AP6110		21F3601		1		1			
CUT ROUND, 1.5 THREAD RELIEF ON MACHINED THREADS							DWG BY				D UKEN				DATE		18-Feb-01									
BREAK EDGES .016 MAX. ON MACHINED WORK							CHK BY				J WIRTH				DATE		18-FEB-01									
REMOVE BURRS, WELD SPLATTER & LOOSE SCALE							APR BY				E ANDERSSSEN				DATE											
IN ACCORDANCE WITH ASME Y14.5M & B46.1																										